

SEMICONDUCTOR TECHNICAL DATA

2N7000

N CHANNEL ENHANCEMENT MODE FIELD EFFECT TRANSISTOR

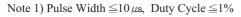
INTERFACE AND SWITCHING APPLICATION.

FEATURES

- · High density cell design for low $R_{DS(\mathrm{ON})}$.
- · Voltage controlled small signal switch.
- · Rugged and reliable.
- · High saturation current capablity.

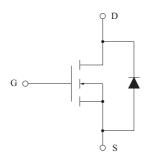
MAXIMUM RATING (Ta=25°C)

CHARACT	SYMBOL	RATING	UNIT		
Drain-Source Voltage		V _{DSS}	60	V	
Gate-Source Voltage	e	V _{GSS}	±20	V	
Drain Current	Continuous	I_D	500	mA	
	Pulsed(Note 1)	I_{DP}	2000		
Drain Power Dissipa	Drain Power Dissipation		625	mW	
Junction Temperature		T _j	150	c	
Storage Temperature Range		T_{stg}	-55~150	c	



4.70 MAX В 4.80 MAX С 3.70 MAX D 0.45 E F 1.00 G 0.85 Н 0.45 14.00±0.50 K 0.55 MAX L 0.45 MAX 1.00 1. SOURCE 2. GATE 3. DRAIN TO-92

EQUIVALENT CIRCUIT



PLEASE HANDLE WITH CAUTION.

THIS TRANSISTOR IS ELECTROSTATIC SENSITIVE DEVICE.

ELECTRICAL CHARACTERISTICS (Ta=25 °C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Drain-Source Breakdown Voltage	$\mathrm{BV}_{\mathrm{DSS}}$	$V_{GS} = 0V, I_D = 10 \mu A$	60	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} =60V, V_{GS} =0V	-	-	1	μA
Gate-Body Leakage, Forward	I_{GSSF}	$V_{GS}=20V, V_{DS}=0V$	-	-	100	nA
Gate-Body Leakage, Reverse	I_{GSSR}	V_{GS} =-20V, V_{DS} =0V	-	-	-100	nA

ELECTRICAL CHARACTERISTICS (Ta=25 ℃) ON CHARACTERISTICS (Note2)

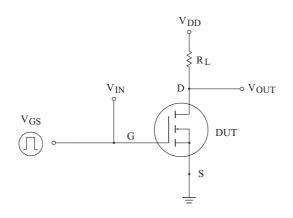
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Threshold Voltage	V _{th}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.1	1.8	2.3	V
Drain-Source ON Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =500mA	-	1.2	1.8	Ω
		$V_{GS}=5V$, $I_D=50$ mA	-	1.5	2.1	
Drain-Source ON Voltage	V _{DS(ON)}	V _{GS} =10V, I _D =500mA	-	0.6	0.9	V
		V_{GS} =5V, I_D =50mA	-	0.075	0.105	
On State Drain Current	$I_{D(ON)}$	$V_{GS}=10V, V_{DS}=\geq 2 V_{DS(ON)}$	500	-	-	mA
Forward Transconductance	g_{FS}	V _{DS} =10V, I _D =500mA	200	580	-	mS
Drain-Source Diode Forward Voltage	V_{SD}	V _{GS} =0V, I _S =200mA (Note1)	-	0.78	1.15	V

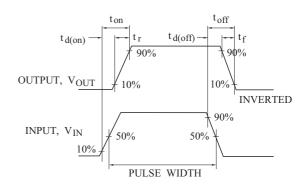
(Note 2) Pulse Test: Pulse Width $\leq 80 \,\mu s$, Duty Cycle $\leq 1\%$

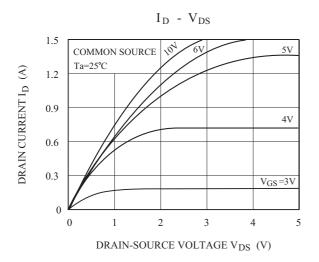
DYNAMIC CHARACTERISTICS

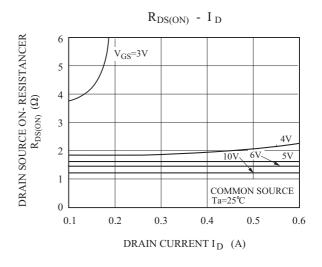
CHARAC	TERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Input Capacitance		C _{iss}		-	47.1	-	
Reverse Transfer Ca	pacitance	C _{rss}	V_{DS} =25V, V_{GS} =0V, f=1MHz	-	3.5	-	pF
Output Capacitance		C _{oss}		-	8.8	-	
Switching Time	Turn-On Time	t _{on}	$V_{DD}=30V, R_L=155 \Omega, I_D=190mA,$	-	8.8	-	nS
	Turn-Off Time	$t_{ m off}$	$V_{GS}=10V$	-	14.8	-	

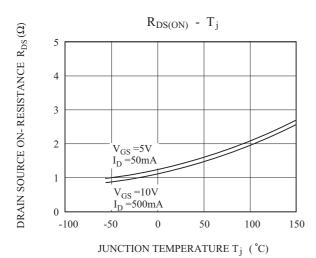
SWITCHING TIME TEST CIRCUIT

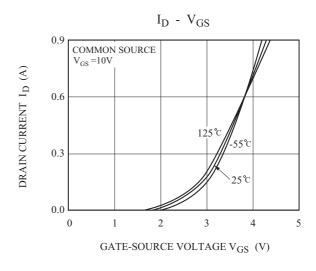


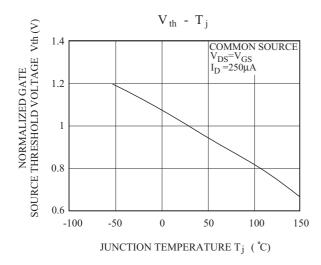


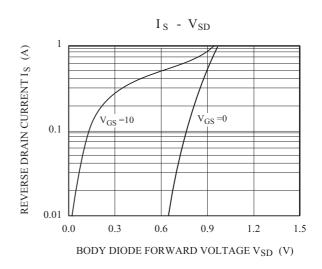


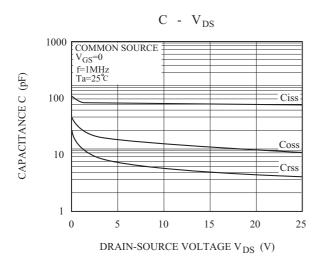


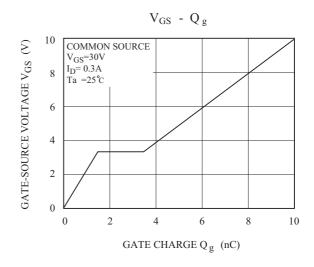


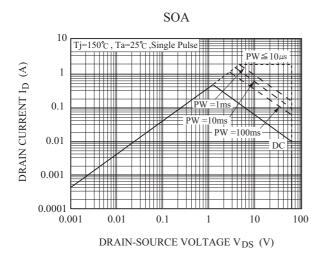


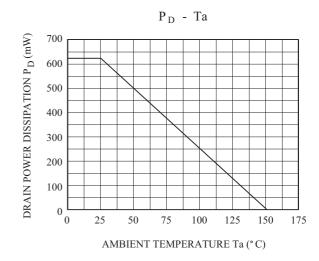












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